


<b>Search Notes</b>  	<b>Application/Control No.</b>  10790711	<b>Applicant(s)/Patent Under Reexamination</b>  FUJINAWA ET AL.
	<b>Examiner</b>  Kaplan, Benjamin A	<b>Art Unit</b>  2109

SEARCHED			
Class	Subclass	Date	Examiner
380	45,281		
713	193		
726	27,30		

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner